

New Jersey Semi-Conductor Products, Inc.

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U.S.A.

2N5397

2N5398

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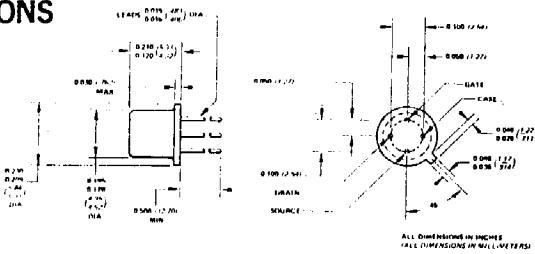
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N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

FOR UHF AMPLIFIER, MIXER AND OSCILLATOR APPLICATIONS AND VIDEO AMPLIFIER APPLICATIONS

- $G_{ps} = 10 \text{ dB}$ Typical (Common Gate) at 450 MHz (2N5397)
- NF = 3 dB Typical at 450 MHz
- $C_{rss} = 1 \text{ pF}$ Typical



PRODUCT CONDITIONING

Units receive the following treatment before final electrical tests:

High Temp Storage: 24 Hours at 150°C 25,000g Acceleration/Impact in the Y₁ Plane
Thermal Shock: +100 to 0°C for 5 Cycles Helium and/or Gross Leak Tests for Hermeticity

*ABSOLUTE MAXIMUM RATINGS (25°C)

Gate-Drain or Gate-Source Voltage	-25 V
Gate Current	10 mA
Total Device Dissipation (Derate 1.7 mW/°C)	300 mW
Storage Temperature Range	-65 to +200°C
Lead Temperature 1/16" from case for 10 sec	300°C

*ELECTRICAL CHARACTERISTICS (25°C unless otherwise specified)

Characteristic	2N5397				2N5398			
	Test Conditions	Min	Max	Unit	Test Conditions	Min	Max	Unit
I_{GSS} Gate Reverse Current	$V_{GS} = -15 \text{ V}, 25^\circ\text{C}$		-0.1	nA	$V_{GS} = -15 \text{ V}, 25^\circ\text{C}$		-0.1	nA
	$V_{DS} = 0 \text{ V}, 150^\circ\text{C}$		-0.1	μA	$V_{DS} = 0 \text{ V}, 150^\circ\text{C}$		-0.1	μA
BV_{GSS} Gate-Source Breakdown Voltage	$I_G = -1 \mu\text{A}, V_{DS} = 0$	-25		V	$I_G = -1 \mu\text{A}, V_{DS} = 0$	-25		V
V_P Gate-Source Pinch-Off Voltage	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ nA}$	-1	-6	V	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ nA}$	-1	-6	V
I_{DSS} Drain Current at Zero Gate Voltage †	$V_{DS} = 10 \text{ V}, V_{GS} = 0$	10	30	mA	$V_{DS} = 10 \text{ V}, V_{GS} = 0$	5	40	mA
$V_{GS(f)}$ Gate-Source Forward Voltage	$I_G = 1 \text{ mA}, V_{DS} = 0$		1	V	$I_G = 1 \text{ mA}, V_{DS} = 0$		1	V
g_{fs} Common-Source Forward Transconductance †	$V_{DS} = 10 \text{ V}, I_D = 10 \text{ mA}, f = 1 \text{ kHz}$	6000	10,000	μmho	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ kHz}$	5500	10,000	μmho
g_{oss} Common-Source Output Conductance			200	μmho			400	μmho
C_{rss} Common-Source Reverse Transfer Capacitance	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$		1.2	pF	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		1.3	pF
C_{iss} Common-Source Input Capacitance	$f = 1 \text{ MHz}$		5	pF			5.5	pF

*HIGH FREQUENCY CHARACTERISTICS at 450 MHz (25°C)

Characteristic	Test Conditions	Min	Max	Unit	Test Conditions			Min	Max	Unit
					Min	Max	Unit			
κ_{iss} Common-Source Input Conductance	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$		2000	μmho				3000		μmho
			400	μmho				500		μmho
		5500	9000	μmho				5000	10,000	μmho
g_{fs} Common-Source Forward Transconductance †										
G_{ps} Common-Source Power Gain (neutralized)	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$ See Page 4	15		dB						
NF Common-Source, Spot Noise Figure (neutralized)	$V_{DG} = 10 \text{ V}, I_D = 10 \text{ mA}$ See Page 4		3.5	dB						

*JEDEC Registered Data

† Pulse test duration: 2 ms.

These devices are manufactured to meet or exceed the requirements of MIL-S-19500.

